

JC05 Rec'd PCT/PTO 17 JUN 2005

INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449	Atty. Docket No. 10191/4188	Serial No. To Be Assigned  <b>10/539495</b>
	Applicant(s) HARTER et al.	
	Filing Date Herewith	Group To Be Assigned

## U. S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
						YES	NO

## OTHER DOCUMENTS

EXAMINER'S INITIALS	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
/JPT/	Built-In Test for VLSI: Pseudorandom Techniques by Paul H. Bardell, William H. McAnney and Jacob Savir; pp. 124 et seq.*
/JPT/	A Linear Code-Preserving Signature Analyzer COPMISR; Hlawiczka et al; VLSI Test Symposium, 1997 - 15 <sup>th</sup> IEEE Monterey, CA USA 27 April - 1 May 1997; pp. 350-355.**
/JPT/	Low Cost BIST for EDAC Circuits; Badura et al; Test Symposium, 1997 (ATS '97), Proceedings, Sixth Asian Akita, Japan 17-19 November 1997; pp. 410-415.**
/JPT/	Utilization of On-Line (Concurrent) Checkers During Built-In-Self-Test and Vice Versa; Gupta et al.; IEEE Transactions on Computers; 1 January 1996; pp. 63-73.**
/JPT/	Design of t-UED/AUED Codes from Berger's AUED Code; Biswas et al.; VLSI Design, 1997, Proceedings, Tenth International Conference on Hyderabad; 4-7 January 1997; pp. 364-369.**
EXAMINER	DATE CONSIDERED
/John P Trimmings/	09/13/2007
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

\*Described in specification.

\*\*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority).